

Photointerrupters(Transmissive)

KODENSHI

SG - 238V

The SG - 238V photointerrupter high - performance standard type, combines high - output GaAs IRED with high sensitive phototransistor.

FEATURES

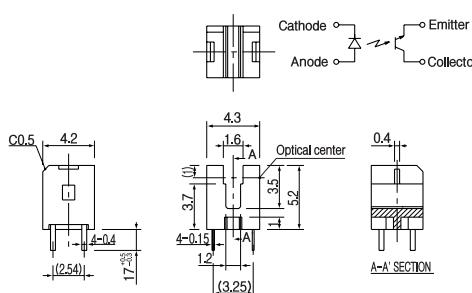
- PWB direct mount type
- GAP : 1.2mm
- Compact

APPLICATIONS

- Cameras
- Video cameras
- Floppy disk drives
- C D - ROM drives

DIMENSIONS

(Unit : mm)



MAXIMUM RATINGS

(Ta=25 °C)

	Item	Symbol	Rating	Unit
Input	Power dissipation	P _D	75	mW
	Forward current	I _F	50	mA
	Reverse voltage	V _R	5	V
	Pulse forward current ¹⁾	I _{FP}	0.5	A
Output	Collector power dissipation	P _C	75	mW
	Collector current	I _C	20	mA
	C - E voltage	V _{CEO}	30	V
	E - C voltage	V _{ECO}	5	V
Operating temp. ²⁾		Topr.	- 20 ~ +85	
Storage temp. ²⁾		Tstg.	- 30 ~ +100	
Soldering temp. ³⁾		Tsol.	260	

¹⁾1. pulse width : t w 100 μ sec. period : T = 10msec.

²⁾2. No icebound or dew ³⁾3. For MAX.5 seconds at the position of 1mm from the package

ELECTRO-OPTICAL CHARACTERISTICS

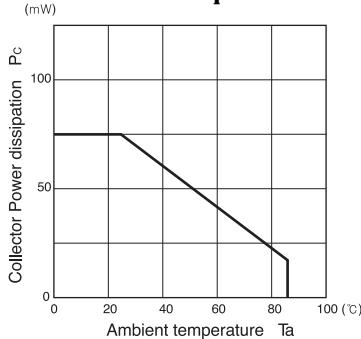
(Ta=25 °C)

	Item	Symbol	Conditions	Min.	Typ.	Max.	Unit.
Input	Forward voltage	V _F	I _F =20mA		1.2	1.4	V
	Reverse current	I _R	V _R =5V			10	μ A
	Peak wavelength	λ	I _F =20mA		940		nm
Output	Collector dark current	I _{CEO}	V _{CE} =10V		1	100	nA
	Light current	I _C	I _F =10mA, V _E =5V, (Non-shading)	0.25		2.5	mA
	Leakage current	I _{CEO}	I _F =10mA, V _E =5V(shading)			10	μ A
Transmissio	C - E saturation voltage	V _{CE(sat)}	I _F =10mA, I _C =0.03mA			0.4	V
	Rise time	T ₁				125	μ sec.
	Fall time	T ₂	V _{CC} =4.4V, I _F =15mA, R=100k			1200	μ sec.

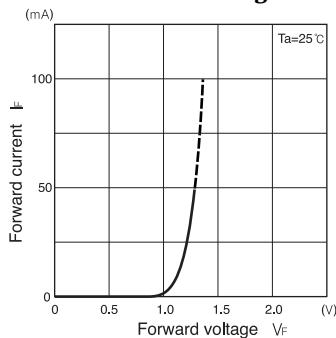
Photo interrupters(Transmissive)

SG - 238V

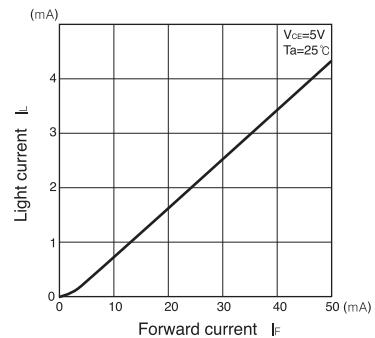
**Collector power dissipation Vs.
Ambient temperature**



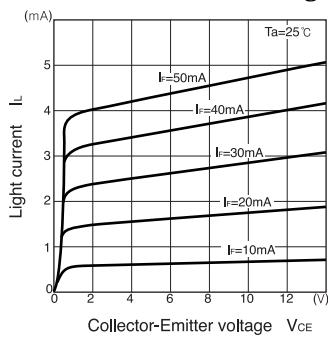
**Forward current Vs.
Forward voltage**



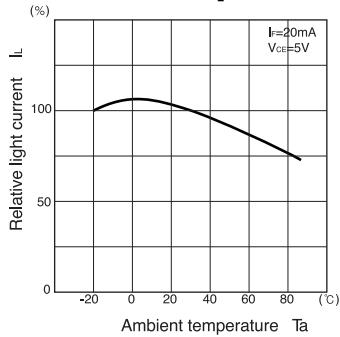
**Light current Vs.
Forward current**



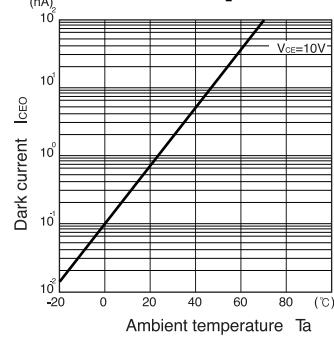
**Light current Vs.
Collector-Emitter voltage**



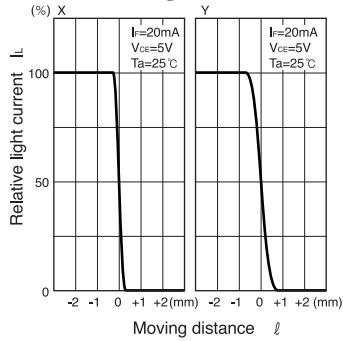
**Relative light current Vs.
Ambient temperature**



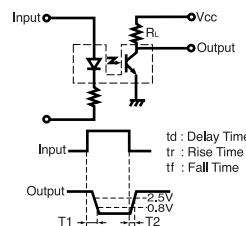
**Dark current Vs.
Ambient temperature**



**Relative light current Vs.
Moving distance**



Switching time measurement circuit



Method of measuring position
detection characteristic

